

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



In re patent application of

Kazuki Yokota

Serial No.: 09/627,456

Group Art Unit: 2877

Filing Date: July 27, 2000

Examiner: Unknown

For: OVERLAY MARK, METHOD OF MEASURING OVERLAY ACCURACY,
METHOD OF MAKING ALIGNMENT AND SEMICONDUCTOR DEVICE
THEREWITH

Assistant Commissioner of Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.99 and pursuant to applicant's duty of disclosure under 37 CFR §1.56, applicant respectfully brings the following document cited in the Korean Office Action and listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. Copy of the listed document is provided herewith for the convenience of the Examiner.

In compliance with the requirements of 37 CFR §1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 35 U.S.C. §1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a translation of portions of an official action by a foreign examiner in which the reference was cited. The relevance to the pending U.S. patent application is that the reference was cited in a foreign patent application on the same subject matter. However, no independent analysis of the reference, the accuracy of the statement of the foreign examiner or the claims of the foreign application under the laws of that country or the United States relative to the subject matter claimed in the present application has been made, the present understanding of the contents thereof by the undersigned being based on the translation of the foreign examiner's comments submitted herewith.

This citation does not constitute an admission that the reference is relevant or material to the claims. This is only cited as constituting related art of which the applicant is aware.

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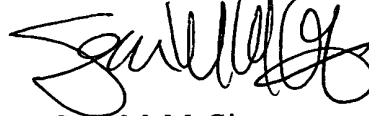
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NEC00P063-TO

I hereby certify that each item of information contained in this Information Disclosure Statement was the first citation of that item by a foreign patent office in a counterpart foreign application, which occurred not more than three months prior to the filing of this statement.

It is respectfully requested that the listed reference be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,



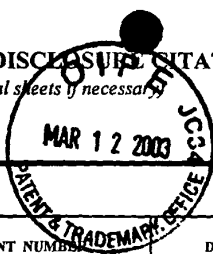
Sean M. McGinn

Registration No. 34,386

Date: 3/12/03
McGinn & Gibb, PLLC
Intellectual Property Law
8321 Old Courthouse Road, Suite 200
Vienna, VA 22182-3817
(703) 761-4100
Customer No. 21254

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)



Docket Number (Optional)

NEC00P06

Application Number

09/627,456

Applicant(s)

Kazuki Yokota

Filing Date

July 27, 2000

Group Art Unit

2877

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,128,280	07/07/1992	Matsumoto et al.			

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FOREIGN PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		Korean Office Action dated December 18, 2002 with Japanese Translation and Partial English Translation.

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.